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Docket No.: 4358-0116P  
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:  
Hai-Wen CHEN et al.

Application No.: 10/727,039

Confirmation No.: 4864

Filed: December 4, 2003

Art Unit: 2625

For: SYSTEM AND METHOD FOR ESTIMATING  
NOISE USING MEASUREMENT BASED  
PARAMETRIC FITTING NON-UNIFORMITY  
CORRECTION

Examiner: Y. J. Couso

**STATUS INQUIRY**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

It is respectfully requested that the attorney named below be advised of the status of the above-identified application. Please advise us of when we might expect to receive an Office Action from the Patent and Trademark Office.

Dated:

NOV 4 2005

Respectfully submitted,

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